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Editors

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Contents

vii	<i>Authors</i>
ix	<i>Symposium Committees</i>
xiii	<i>Conference Committee</i>

TRANSMISSION AND INTERFEROMETRIC STUDIES

10815 03	CGH and stitching technique: powerful combination enabling full-surface figure measurements of certain classes of aspheres (Invited Paper) [10815-3]
10815 04	Optical design and accuracy analysis of interferometric star tracker [10815-4]
10815 05	Calibration of probe misalignment in point-diffraction interferometer [10815-5]
10815 06	Effect of defects on filtering performance of one-dimensional photonic crystals [10815-6]
10815 07	Surface plasmon-assisted transmission in dual metallic film [10815-7]

LENS DESIGN AND FABRICATION METHODS

10815 0A	Design of multizone soft contact lens to slow myopia progression [10815-10]
10815 0B	Wavefront predictions for the automated assembly of optical systems [10815-11]

ASPECTS OF TELESCOPIC OPTICS

10815 0D	Large dynamic range wavefront sensing using Shack-Hartmann wavefront sensor based on pattern correlations (Invited Paper) [10815-13]
10815 0E	Optical design for three sub-mirror sparse aperture with freeform surface [10815-14]
10815 0F	Stray light suppression of a compact off-axis telescope for a satellite-borne instrument for atmospheric research [10815-15]
10815 0G	Phasing error detection for segmented telescopes [10815-16]

ILLUMINATION RELATED ISSUES

- 10815 OH **Color temperature changeable adaptive driving beam for enhanced human perception (Invited Paper)** [10815-17]
- 10815 OI **Characterization of angle-resolved measurement of diffuse reflected light (Invited Paper)** [10815-18]
- 10815 OJ **Improvement of color gamut in laser quantum dots backlight display (Invited Paper)** [10815-19]
- 10815 OK **Freeform lens design for laser diode beam shaping (Invited Paper)** [10815-20]
- 10815 OL **Acousto-optical tunable filter for a swept light source with variable transmission function** [10815-21]
- 10815 OM **Annular oblique epi-illumination design for ultra-large-scale and high-resolution fluorescence microscopy** [10815-22]

STRAY LIGHT ANALYSIS AND TEST TECHNIQUES

- 10815 OP **Diffraction method for inspecting the defects of lenses with various curvature** [10815-25]
- 10815 OQ **Systematic parameter calibration in the wavefront testing with reverse Hartmann test** [10815-26]
- 10815 OR **Monte Carlo calculation on stray radiation scattered by the baffle with a heterotypic surface for uncooled infrared system** [10815-28]
- 10815 OS **RGB camera-based functional imaging of in vivo biological tissues (Invited Paper)** [10815-66]

IMAGING STUDIES AND IMPLEMENTATION

- 10815 OT **Multi-dimensional digital holographic microscopy (Invited Paper)** [10815-2]
- 10815 OU **Analysis of the visual perception conflicts in designing mixed reality systems** [10815-29]
- 10815 OW **Design of UV LED illumination system for direct imaging lithography** [10815-31]

POSTER SESSION

- 10815 0X **Scanning distortion analysis of infrared thermal imagers systems** [10815-32]
- 10815 0Y **Development and practical test of portable laser communication optical system** [10815-33]
- 10815 11 **A GEO satellite working state detection method based on photometric characteristics**
[10815-37]
- 10815 12 **The construction of frontal components of objectives for microscope: optical design** [10815-38]
- 10815 13 **The possibility of expanding the spectral range for lens microscope objectives: examples of optical design** [10815-39]
- 10815 15 **The field mosaic method of wide-angle telescope array for typical track general survey**
[10815-41]
- 10815 16 **Modeling and analysis for the mirror tilt angle error of the image mapper** [10815-42]
- 10815 17 **Mode interactions in a three-layered slab waveguide with periodic structures** [10815-43]
- 10815 18 **Multi-type hyperspectral imaging integrated system** [10815-44]
- 10815 1A **Simulation of eye's wavefront aberration measurement based on annular radial shearing interferometry** [10815-46]
- 10815 1B **Optimizing double freeform surfaces for reducing deviations in ray-mapping method**
[10815-47]
- 10815 1E **Tolerances and alignment method for high-aperture hybrid diffractive-reflective objective**
[10815-51]
- 10815 1F **Method of object MRTD-testing for thermal infrared imager** [10815-52]
- 10815 1H **Thermal stress of MOEMS accelerometers based on grating interferometric cavity** [10815-54]
- 10815 1M **Comparative analysis of mid-spatial frequency errors measurement using multiple phase retrieval algorithms** [10815-59]
- 10815 1O **Continuous zoom laser beam shaper with microlens arrays** [10815-61]
- 10815 1P **Peculiarities of optical element manufacturing in the Chinese optical industry** [10815-62]
- 10815 1Q **Optimal parameter solution for optical design of testing large-aperture off-axis aspheric mirror with computer-generated holograms** [10815-63]
- 10815 1R **Stretchable phase-mode Fresnel zone plates for focus tuning** [10815-64]

10815 1S

Freeform surface optical design of Zernike polynomials based on nodal aberration theory
[10815-65]